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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/762,568	01/23/2004	Gert-Jan Heerens	081468-0307814	3196
909	7590 09/01		EXAMINER	
PILLSBUI	RY WINTHROP S	NGUYEN, HUNG		
P.O. BOX 1	0500			
MCLEAN, VA 22102			ART UNIT	PAPER NUMBER
,	,		2851	
			DATE MAILED: 09/01/2005	

Please find below and/or attached an Office communication concerning this application or proceeding.

•		Application No.	Applicant(s)	
		10/762,568	HEERENS ET AL.	
Office Act	ion Summary	Examiner	Art Unit	
		Hung Henry V. Nguyen	2851	
The MAILING D Period for Reply	ATE of this communication app	pears on the cover sheet with the c	orrespondence address	
A SHORTENED STAT THE MAILING DATE (  Extensions of time may be a after SIX (6) MONTHS from i  If the period for reply specific  If NO period for reply is spec  Failure to reply within the set	OF THIS COMMUNICATION. vailable under the provisions of 37 CFR 1.13 the mailing date of this communication. It is above is less than thirty (30) days, a reply iffed above, the maximum statutory period vor extended period for reply will, by statute fice later than three months after the mailing	Y IS SET TO EXPIRE 3 MONTH(s) 36(a). In no event, however, may a reply be time by within the statutory minimum of thirty (30) days will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE grate of this communication, even if timely filed.	ely filed s will be considered timely. the mailing date of this communication. O (35 U.S.C. § 133).	
Status				
2a) ☐ This action is FI 3) ☐ Since this applic	cation is in condition for allowar	action is non-final.  nce except for formal matters, pro		
ciosed in accord	lance with the practice under E	Ex parte Quayle, 1935 C.D. 11, 45	3 U.G. 213.	
Disposition of Claims				
4a) Of the above 5) ☐ Claim(s) 6) ☑ Claim(s) <u>1-21</u> is 7) ☐ Claim(s)	/are rejected.	wn from consideration.		
Application Papers				
10) The drawing(s) fi Applicant may not Replacement draw	request that any objection to the wing sheet(s) including the correct	r. a)⊠ accepted or b)□ objected drawing(s) be held in abeyance. See ion is required if the drawing(s) is obj aminer. Note the attached Office	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).	
Priority under 35 U.S.C.	§ 119	•		
12) Acknowledgmen a) All b) Son 1. Certified of 2. Certified of 3. Copies of application	t is made of a claim for foreign ne * c) None of: copies of the priority documents the certified copies of the priority documents the literational Bureau	s have been received in Application rity documents have been received	on No d in this National Stage	
Attachment(s)  1) Notice of References Cite	d (PTO-892)	4) Interview Summary	(PTO_413)	
2) D Notice of Draftsperson's P	to (FTO-632) Patent Drawing Review (PTO-948) atement(s) (PTO-1449 or PTO/SB/08)	Paper No(s)/Mail Da		

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#### **DETAILED ACTION**

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### Continued Examination Under 37 CFR 1.114

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on July 26, 2005 has been entered.

#### Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
  - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 1-21 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shiraishi (U.S.Pat. 6,842,221) in view of Yamamoto (U.S 2004/0150823 A1).

With respect to claims 1-21, Shiraishi (figure 1) discloses an exposure apparatus comprising substantially all of the limitations of the instant claim such as: a patterning device (R) configured to impart a beam of radiation (EL) with a desired pattern in its cross-section, the patterning device being supported by a support structure (14); a projection system (PL) configured to project the patterned beam onto a target portion of a substrate (W); a conditioned chamber (15) that houses the supporting structure; an actuator (see col.24, lines 24-34) configured to introduce the patterning device (R) into the conditioned chamber (15) and an

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alignment system disposed outside the conditioned chamber (15), to align the patterning device with the projected beam of radiation (see col.38, lines 47-50). Shiraishi further teaches the actuator includes an actuator arm having a carrier structures for supporting and moving the patterning device (R) from the alignment system to the support structure (see col.24, lines 24-34) and the carrier structure is provided with fixation device configured to secure the patterning device to the carrier structure and a docking system is provided to dock the carrier structure (see figure 9). Moreover, Shiraishi teaches the conditioned chamber comprising a reduced pressure environment (see col.25, lines 30-63) and a reduced particle concentration environment (see col.35, lines 5-11). Shiraishi does not expressly disclose "determining position and orientation of the reticle relative to a reference point on a carrier structure that supports the reticle during the introduction of the reticle into the conditioned chamber and adjusting the position and orientation of the reticle in accordance with the reference point. Yamamoto discloses an exposure apparatus having an alignment system (33, 34 and 40) for aligning the reticle (5) with the projected patterned beam of radiation by determining position and orientation of the reticle relative to a reference point (3) on a carrier structure (2) that supports the reticle (5) during the introduction of the reticle into exposure station and adjusting the position and orientation of the reticle based on the reference point/pin (3). In view of such teachings, it would have been obvious to one having ordinary skill in the art at the time the invention was made to combine the teachings of Shiraishi and Yamamoto to obtain the invention as specified in the above-mentioned claims. It would have been obvious to a skilled artisan to employ the alignment system of Yamamoto into the lithographic apparatus of Shiraishi for the purpose of pre-alignment of the reticle with respect to

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the transporting device during the introduction of the reticle into the chamber and thus a high accurate alignment of the reticle to the stage chamber can be obtained.

## Response to Amendment/Argument

- 4. Applicant's amendment filed July 5, 2005 has been entered. Applicant's arguments with respect to prior art rejections have been carefully reviewed but have been traversed in view of new ground of rejection as set forth above.
- 5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Hung Henry V. Nguyen whose telephone number is 571-272-2124. The examiner can normally be reached on Monday-Friday (First Friday off).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Judy Nguyen can be reached on 571-272-2258. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Hung Henry V Nguyen

Primary Examiner

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hvn 8/28/05